



1. Title:	AIXUV's Tools for EUV-Reflectometry
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3. Abstract body:

AIXUV GmbH and partners developed several tools for EUV-reflectometry in different designs for various types of applications. The range of tools is starting with the affordable, flexible, and compact reflectometers for laboratory use (CEUVR) and is including the high end fully automated high speed reflectometer for EUV mask blanks (MBR) that is fully compliant with the SEMI-standard P38 for EUV mask blank metrology and suited for daily in-fab use.

In this paper the different concepts will be discussed and the performance of the systems will be presented. The paper will focus on the upgrades of the mask blank reflectometer for being used on structured masks including smaller spot size as well as improved accuracy and precision. The compliance with the ITRS metrology roadmap is discussed.

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